



INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	Docket Number (Optional) TWI-8520	Application Number 10/717,316
	Applicant(s) Allan Rosencwaig et al.	
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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	BA	WO 95/00681	01/05/1995	PCT	C23G	1/00		
	BB	10-137704	11/08/1996	Japan (see Dialog Abstract in IDS text)	B08B	3/12		
	BC	WO 98/05066	02/05/1998	PCT	H01L	21/66		
	BD	WO 99/35677	07/15/1999	PCT	H01L	21/306		
	BE	4-357836	12/10/1999	Japan	H01L	21/304	Translation	

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

	BF	K. Imen et al., "Laser-assisted micron scale particle removal," <i>App. Phys. Lett.</i> , Vol. 58, No. 2, 14 January 1991, pp. 203-205.

Examiner	Date Considered 28 OCT. 2004
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	